

Fig. 1A

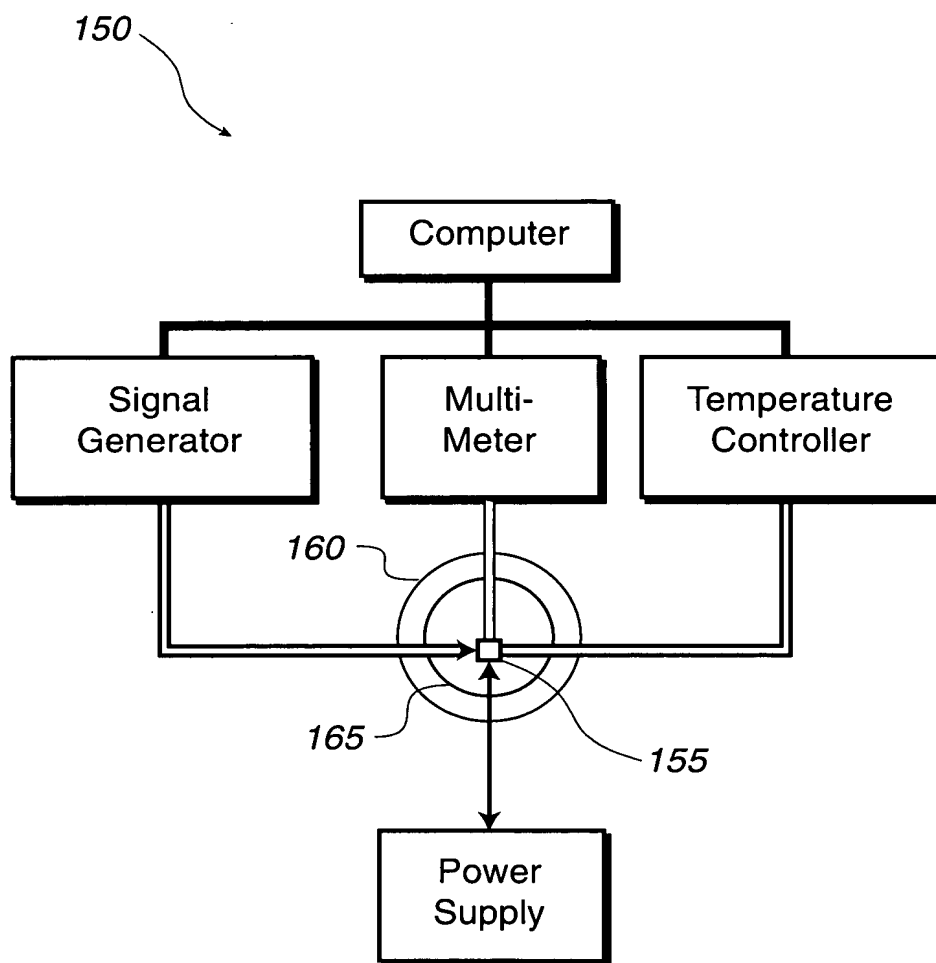


Fig. 1B



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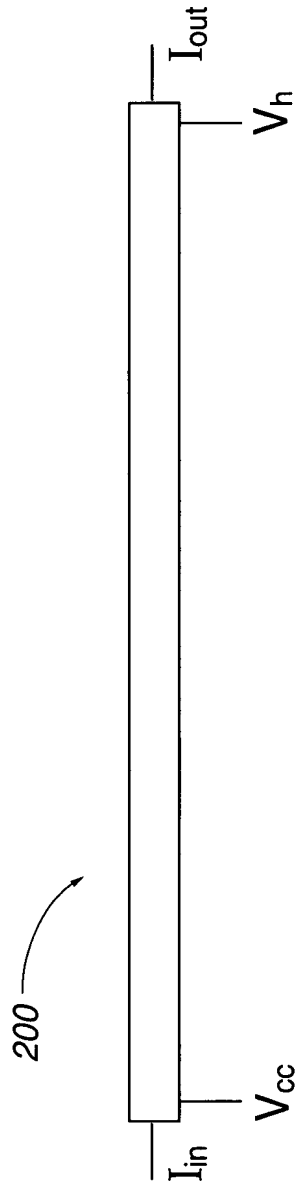


Fig. 2A

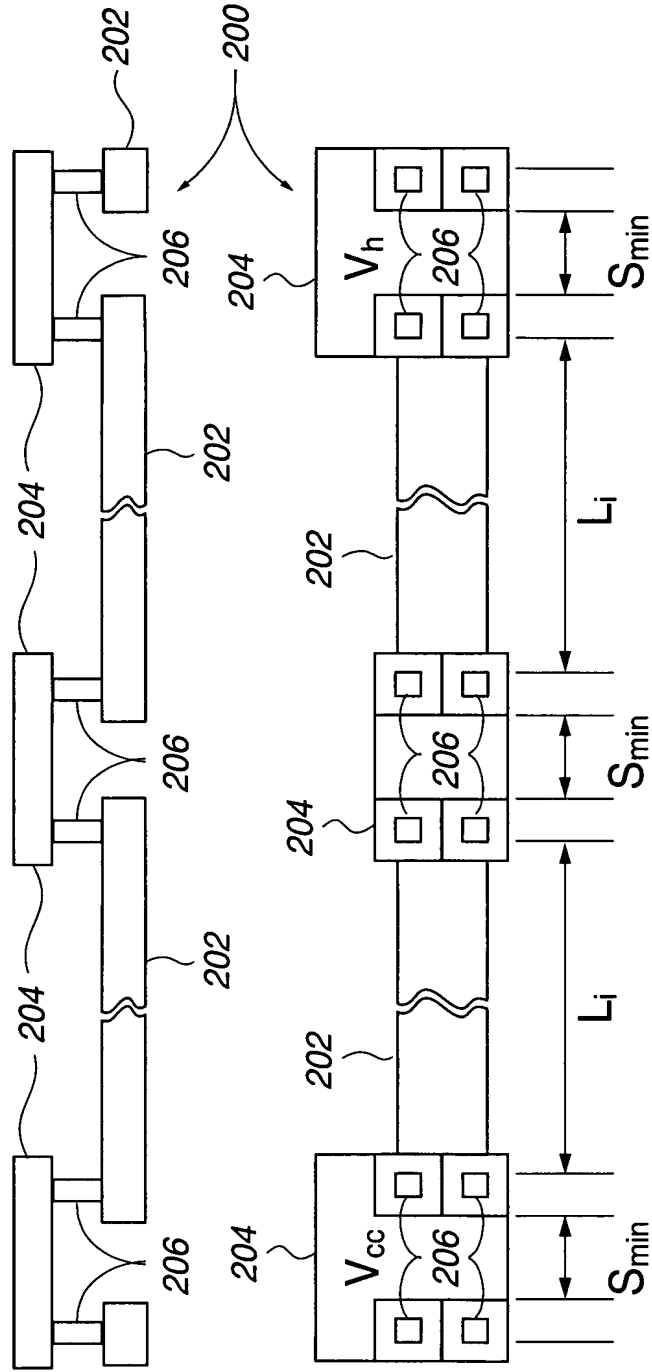


Fig. 2B

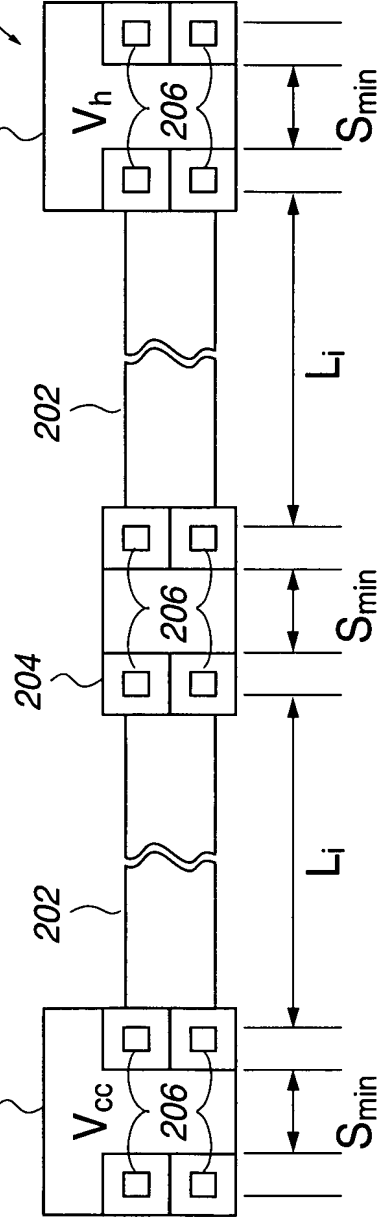
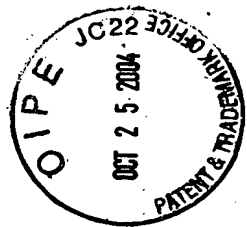


Fig. 2C



INTEGRATED ELECTROMIGRATION LENGTH EFFECT
TESTING METHOD AND APPARATUS
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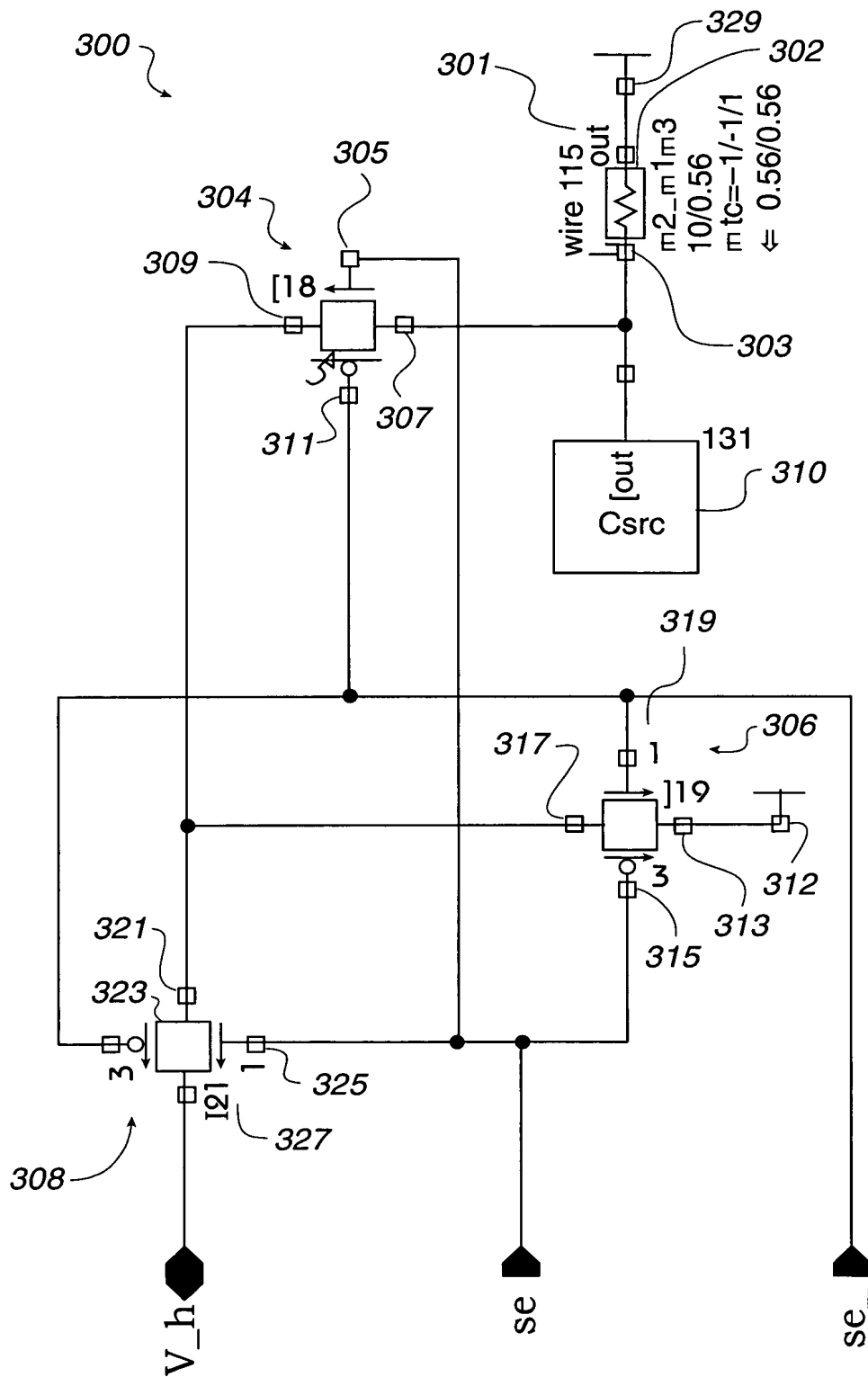
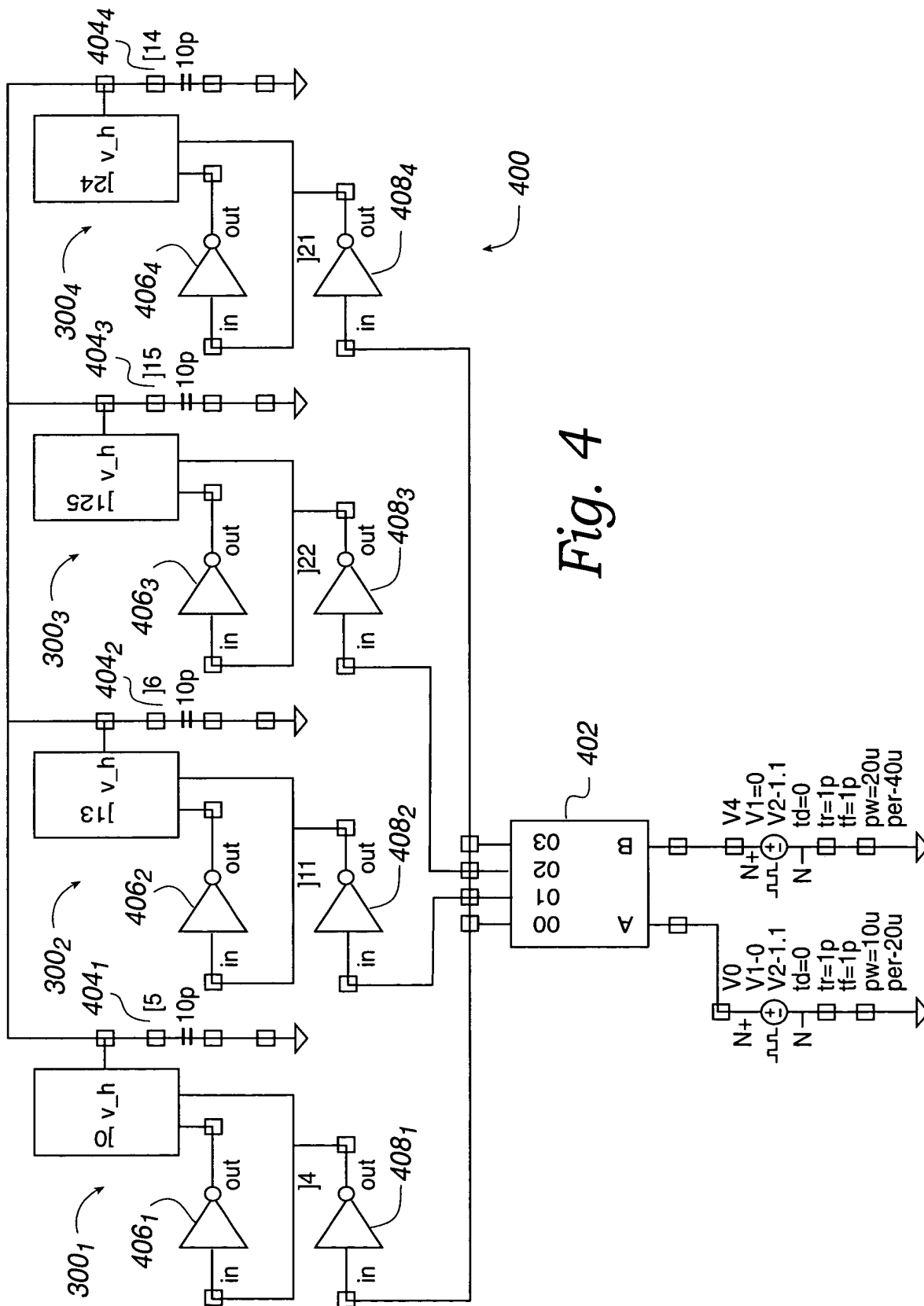


Fig. 3



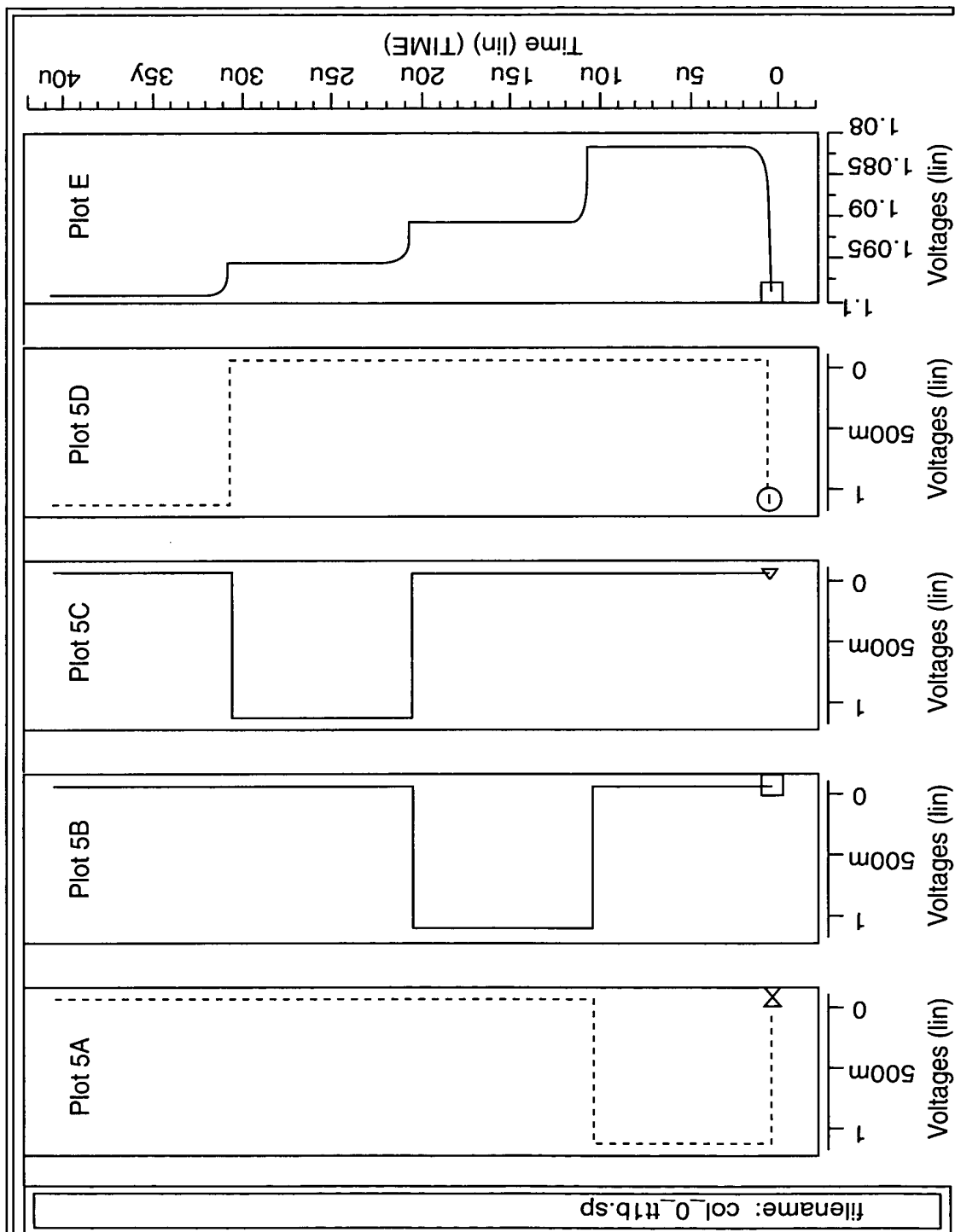
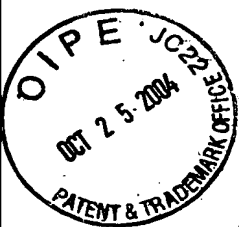


Fig. 5



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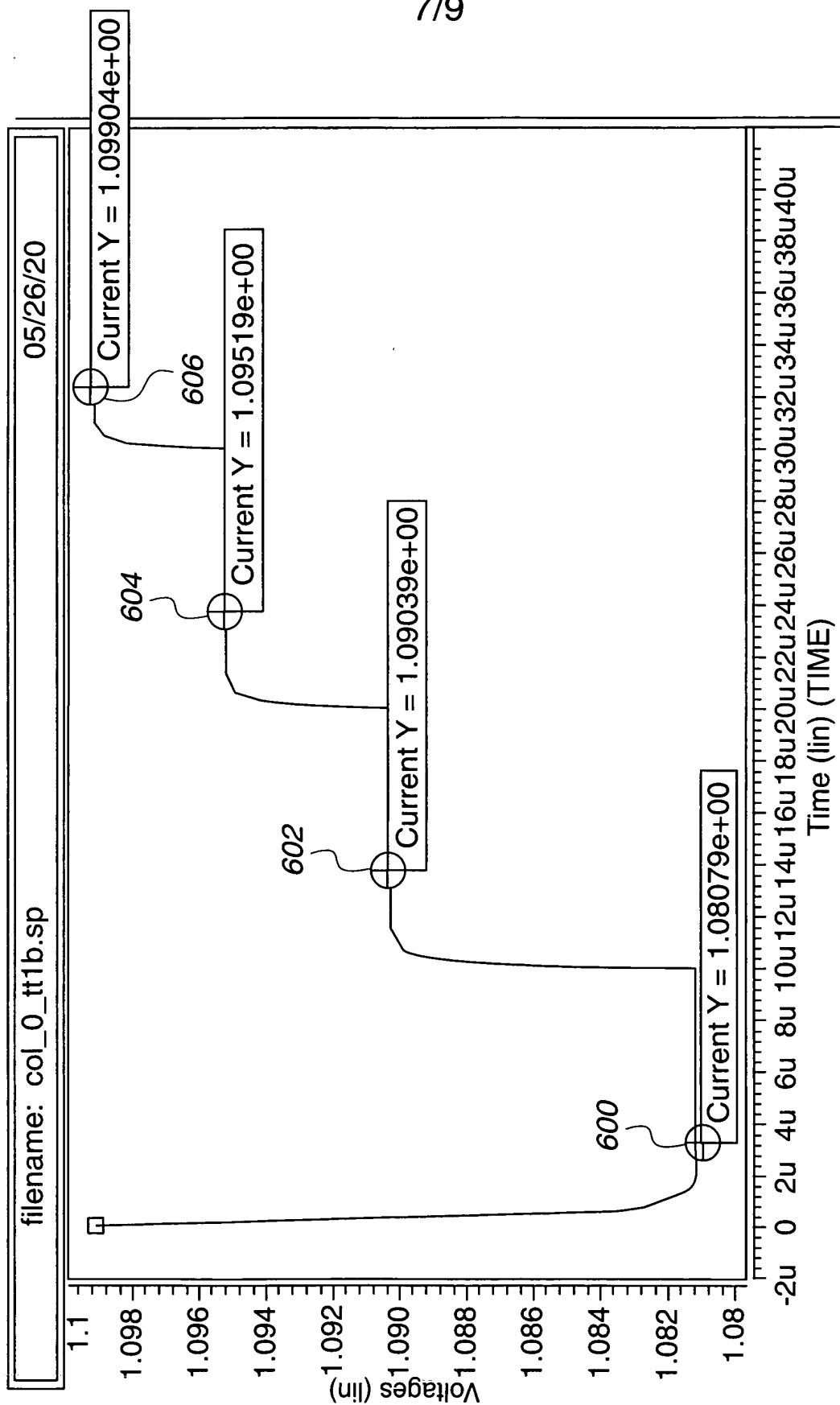
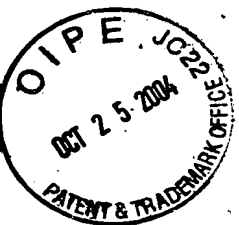


Fig. 6



INTEGRATED ELECTROMIGRATION LENGTH EFFECT
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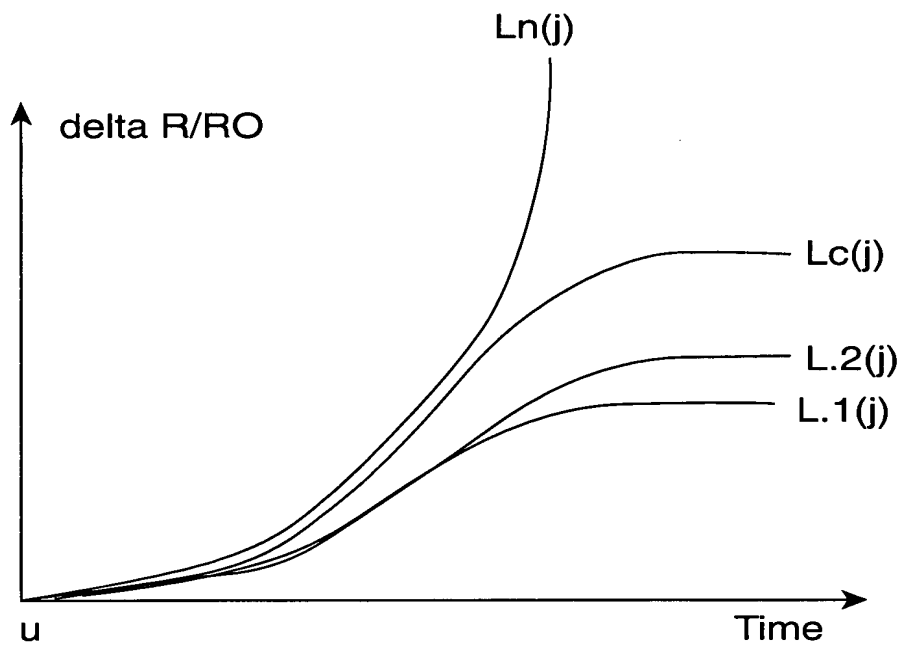


Fig. 7

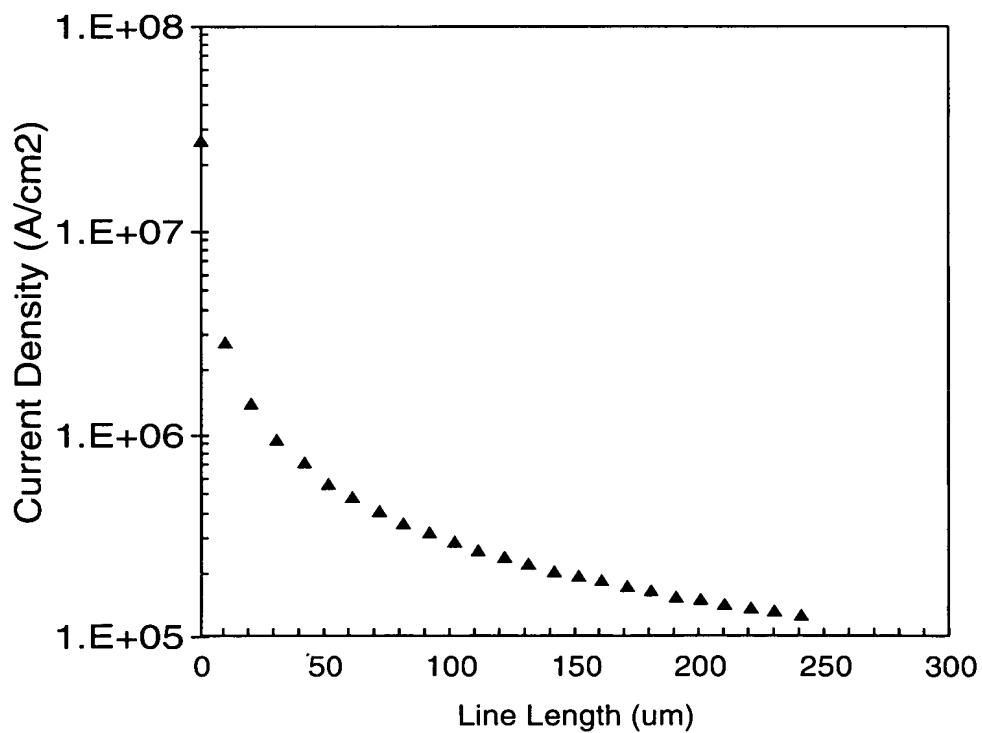


Fig. 8

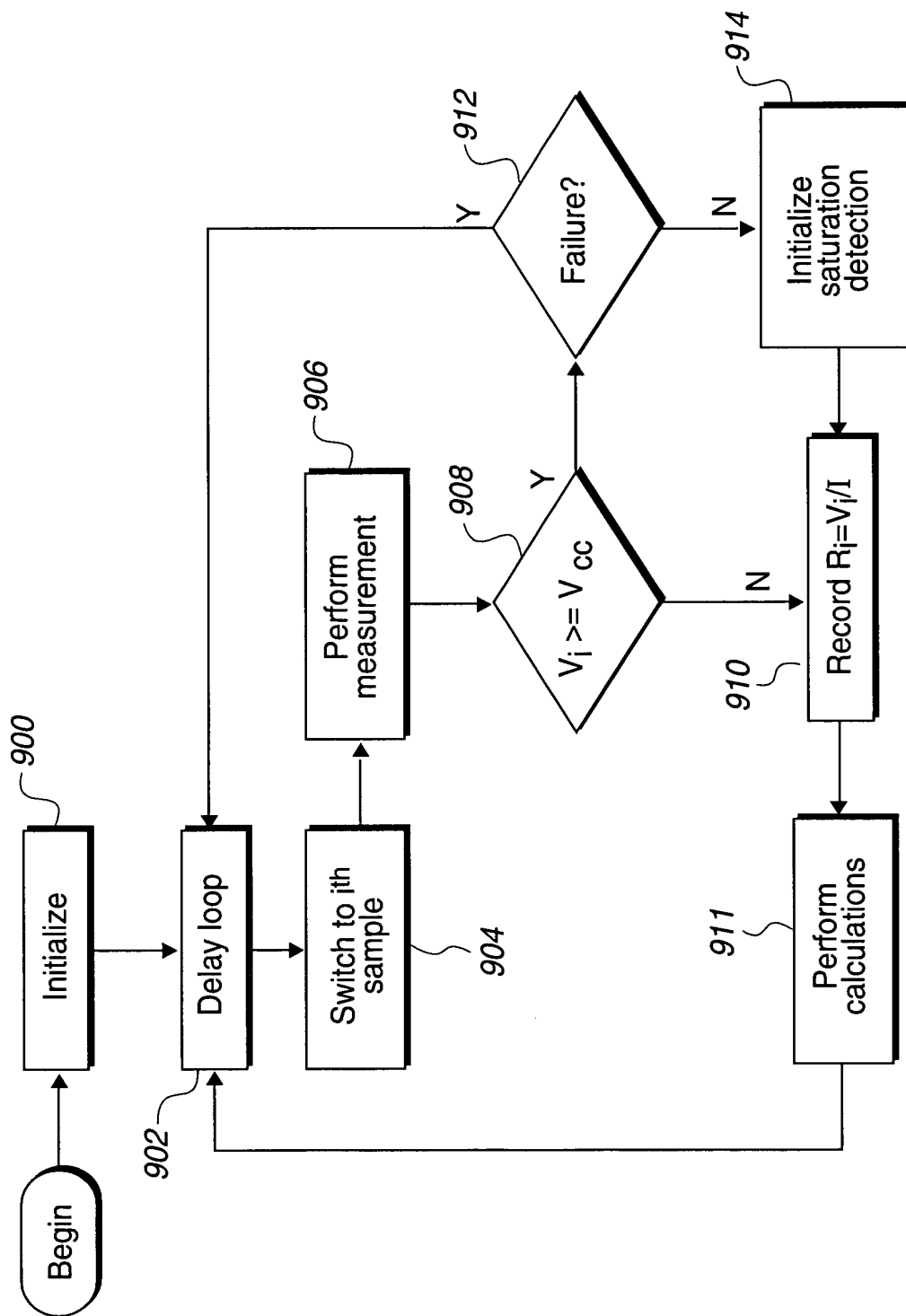


Fig. 9